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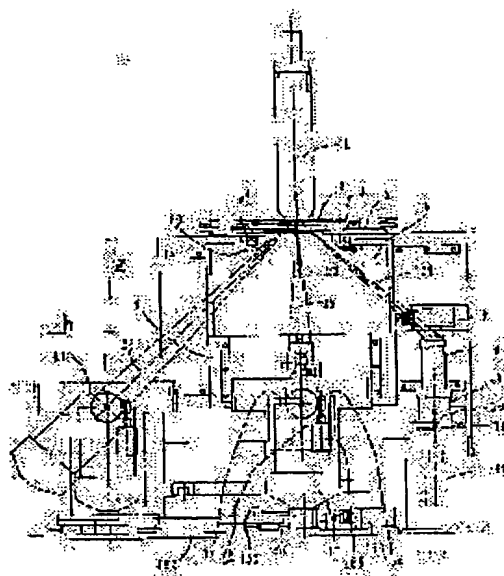
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(54) X-RAY LAMINOGRAPHIC DEVICE

(57)Abstract:

PROBLEM TO BE SOLVED: To perform observation of an X-ray laminogram and a radioscopic image from an optional angle by means of a single inspection device.

SOLUTION: This device is provided with a laminographing unit and a radioscopic image photographing unit. By means of the laminographing unit is provided with a hollow rotary shaft turning an object to be measured below a transmission X-ray source, an XY stage XY-positioning the object to be measured horizontally on the rotary shaft, a Z stage moving the hollow rotary shaft vertically, and an X-ray detection face horizontally arranged in the diagonal lower part below the X-ray source, the detected X-ray image is turned synchronously with the object to be measured for providing a laminogram. The radioscopic image photographing unit is arranged in the symmetrical direction to the X-ray laminographing unit while using the vertical line from the X-ray emission point in the X-ray source as an axis of symmetry. The radioscopic image photographing unit can be moved horizontally, and according to this horizontal shift, a radioscopic image photographing X-ray detection part is always directed toward the X-ray source. In addition, a measurement point is moved onto an X-ray optical axis connecting the radioscopic image photographing X-ray detection part and the X-ray emission point together.



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